

Hardware Technical Specification

ART OBJECT SCANNING AND ANALYSIS SYSTEM

CONCIERGE SPECTRAL IMAGING SERVICE

Spectral measurement and analysis of the μ m-dimensioned pixel specimens that comprise a work of art

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CSIS is an imaging and analysis service for use by museums and other repositories of high value art work. It uses a device called a *Spectral Scanner* to both capture spectra reflected off art objects and analyze the materials used to make the objects. The system uses specialized area sensors to spectrally image artwork in the X-Ray, Ultra Violet, Visible and Infrared energy bands and custom scientific instruments to perform non-destructive materials analysis of the objects. For security and logistical reasons the scanner is setup at a client's site, thus minimizing the amount of time high value artwork is either not on display or otherwise normally secured.

CSIS HARDWARE SPECIFICATIONS

<i>Spectral range</i>	X-Ray through Infrared
<i>Spectral resolution</i>1KeV X-Ray, 1nm/5nm – UV, Visible, IR
<i>Photodynamic range</i>	3.84 [log10(S/N)]
<i>Photodynamic resolution</i> ..	12 bits
<i>Vis Dmax</i>	4.3 (from measurements of Wrattan 96 3.0 ND filter)
<i>Light sources</i>	X-Ray, Deuterium, Xenon, Infrared
<i>Illuminating/viewing system</i> (Vis)	Transmissive: 0/0 (0° illumination/0° viewing angle) Reflective: 45/0 (45° illumination/0° viewing angle)
<i>Repeatability/Vis</i>	Spectral reflectance or transmittance: within .1%
<i>(white point measure)</i>	Colorimetric values: within ΔE^*ab 0.1
<i>Spatial resolution</i>	Pixel measurement area: 15 μ m, 35 μ m, 70 μ m
<i>Mechanical repeatability</i> ..	$\pm .001"$ over area measured
<i>Pixel resolution</i>	360, 720, 1,814 ppi
<i>Microscopic enlargement</i> ..	3X – 7,000X
<i>Effective measuring area</i> ..	4'x8'
<i>International standards</i>	CIE: Publication CIE 015:2004 ISO: 11664, Parts 1 – 5, 10526:2007 ASTM: E 308 - 08, E 1347-06, E 1164 ANSI: CGATS.5-2009 ICC: ISO 15076-1:2010, ICC v4
<i>Trade standards</i>	ColorSync 2.5 and above, ICM 2.0 and above, TIFF MS
<i>OS Compatibility</i>	Windows, MAC OS, Unix, Linux
<i>Measuring modes</i>	Area measurement mode/imaging, Single Measurement Mode/material analysis
<i>Measuring rate</i>	3.28 minutes/sq ft at 360 ppi
<i>Data presentation</i>	Graphical, animated or numerical
<i>Vis</i>	Colorimetric coordinate systems: L*a*b*, sRGB (optional: XYZ, Yxy, L*u*v*, HVC, Device RGB /CMYK)
<i>Measurement conditions</i> ..	Illuminants: CIE Standard Illuminants A, C, D ₆₅ (Vis) also D ₅₀ , D ₅₅ , D ₇₅ , F ₂ , F ₇ , F ₁₁
<i>Environmental</i>	Observers: CIE 2° or 10° Standard Observers Temperature: 60° - 80° F (15° - 26° C) Relative humidity: 20 - 80%
<i>Electrical draw</i>	110V - 60 Hz 20 amps 2,400 watts
<i>Physical</i>	Length: 14' Height: 8' Width: 9' Weight: 975 lbs
<i>Integrated host</i>	Rack mounted server array
<i>Applications</i>	Spectral measurement and spectral analysis of high value original works of art, artwork identification, reproduction, authentication, conservation, restoration, documentation

Specifications subject to change without notice.
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